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THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANTS: VON AMMON ET AL -9 EXAMINER: J. MONDT  
SERIAL NO.: 09/813,240 GROUP: 2826  
FILED: MARCH 20, 2001  
TITLE: SEMICONDUCTOR WAFER MADE FROM SILICON AND METHOD FOR  
PRODUCING THE SEMICONDUCTOR WAFER

SUBMISSION OF SUPPLEMENTAL INFORMATION DISCLOSURE  
STATEMENT OF DR. WOLFGANG STAUDACHER

Mail Stop Fee Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

Applicants wish to bring to the attention of the Patent Examiner the attached Information Disclosure Statement, duly signed by Dr. Wolfgang Staudacher, along with the eight references and their corresponding English Language Abstracts, listed on the enclosed Form PTO-1449 and attached thereto.

The relevance of these references is that they were cited in the corresponding Japanese patent application and the Office Action of the Japanese Patent and Trademark Office

Since this Information Disclosure Statement is being filed after a first Office Action, the official fee of \$180.00 is enclosed. The Commissioner is hereby authorized to charge Deposit Account No. 03-2468 for any additional fees or credit any overpayment in connection with this IDS.



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It is respectfully requested that the foregoing Information Disclosure Statement be incorporated into the official file of the present patent application.

Respectfully submitted,  
Wilfred VON AMMON ET AL

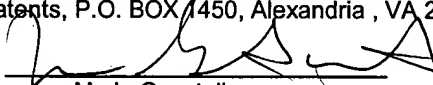


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Attorneys for Applicant

- Enc: 1) Check in the amount of \$180.00  
2) Supplemental Information Disclosure Statement of Dr.  
Wofgang Staudacher  
3) Form PTO-1449  
4) 8 references with English Language Abstract

I hereby certify that this correspondence is being deposited with the U.S. Postal Service as first class mail in an envelope addressed to: Commissioner of Patents, P.O. BOX 1450, Alexandria, VA 22313 -1450, on February 9, 2004.

  
Maria Guastella

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In re application of:

VON AMMON ET AL

Serial Number: 09/813,240

Group Art Unit: 2811

Filed: March 20, 2001

For: SEMICONDUCTOR WAFER MADE FROM SILICON AND METHOD FOR  
PRODUCING THE SEMICONDUCTOR WAFER

Information Disclosure Statement

Honorable Commissioner of Patents and Trademarks  
Washington, D.C. 20231

Sir or Madam:

I, Wolfgang Staudacher, associated with the preparation and prosecution of the above-identified application, residing at Seebauerstraße 4, 81735 München, Germany, wish to call the attention of the Patent Examiner to the references enumerated on the enclosed PTO Form-1449.

I believe the documents enumerated on the enclosed Form PTO-1449 and attached thereto, are cited in the enclosed Office Action of the Japanese Patent and Trademark Office and may be material to the examination of the application.

Therefore, it is respectfully requested that the foregoing Information Disclosure Statement be considered by the Examiner and incorporated into the file of this application.

I wish to comment as follows concerning the prior art references enumerated on PTO Form-1449:

For JP 11-189495 a Patent Abstract of Japan is enclosed.

For JP 07-247197 a Patent Abstract of Japan is enclosed.

For JP 07-066256 a Patent Abstract of Japan is enclosed.

For JP 07-126094 a Patent Abstract of Japan is enclosed.

For JP 57-017497 a Patent Abstract of Japan is enclosed.

For JP 05-294780 a Patent Abstract of Japan is enclosed.

For JP 06-271399 a Patent Abstract of Japan is enclosed.

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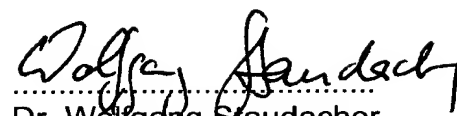
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For JP 10-098047 a Patent Abstract of Japan is enclosed.

Signed this 14<sup>th</sup> day of November 2003.

  
.....  
Dr. Wolfgang Staudacher

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FORM PTO-1449  
(REV. 7-80)DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. : ST 10015

SERIAL NO. 09/813,240

## LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT : VON AMMON ET AL - 9

FILING DATE: 03/20/2001

GROUP: 2811

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
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	AG						
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	AI						
	AJ						
	AK						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AL	11-189495	7/13/99	Japan				
	AM	07-247197	9/26/95	Japan				
	AN	07-066256	3/10/95	Japan				
	AO	07-126094	5/16/95	Japan				
	AP	57-017497	1/29/82	Japan				

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	AR		Patent Abstract of Japan corresponding to JP 11-189495
	AS		Patent Abstract of Japan corresponding to JP 07-247197
	AT		Patent Abstract of Japan corresponding to JP 07-066256

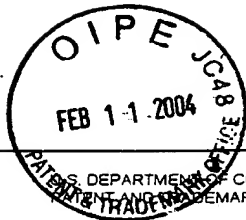
EXAMINER

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FORM PTO-1449  
(REV. 7-80)U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO. : ST 10015SERIAL NO. 091813,240

## LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT : VON AMMON ET AL - 9FILING DATE: 03/20/2001 GROUP: 2811

## U.S. PATENT DOCUMENTS

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## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AL	<u>05-294780</u>	<u>11/9/93</u>	<u>Japan</u>				
	AM	<u>06-271399</u>	<u>9/27/94</u>	<u>Japan</u>				
	AN	<u>10-098047</u>	<u>4/1998</u>	<u>JAPAN</u>				
	AO							
	AP							

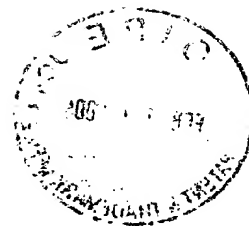
## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	AR		<u>Patent Abstract of Japan corresponding to JP 07-126094</u>
	AS		<u>Patent Abstract of Japan corresponding to JP 57-017497</u>
	AT		<u>Patent Abstract of Japan corresponding to JP 05-294780</u>

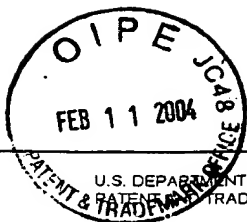
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FORM PTO-1449  
(REV. 7-80)U.S. DEPARTMENT OF COMMERCE  
PATENT & TRADEMARK OFFICEATTY. DOCKET NO. : *ST 10015*SERIAL NO. *091813,240*

## LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT : *VON AMMON ET AL - 9*FILING DATE: *03/20/2001*GROUP: *2811*

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							YES	NO
	AL							
	AM							
	AN							
	AO							
	AP							

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	AR		<i>Patent Abstract of Japan corresponding to JP 061-271399</i>
	AS		<i>Patent Abstract of Japan corresponding to JP 10-098047</i>
	AT		

EXAMINER

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